



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei YAMAZAKI et al. Art Unit : 2813
Serial No. : 09/769,765 Examiner : Laura Schillinger
Filed : January 26, 2001
Title : SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT


Applicants submit the references listed on the attached form PTO-1449.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

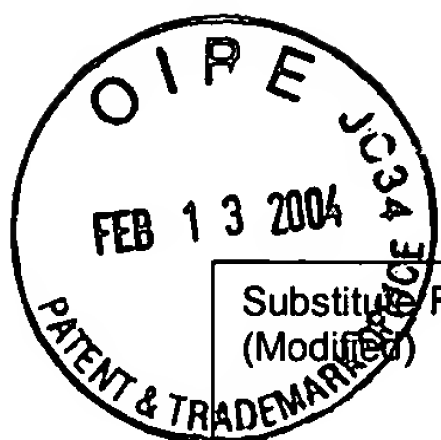
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Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
12732-008001Application No.
09/769,765**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Shunpei YAMAZAKI et al.Filing Date
January 26, 2001Group Art Unit
2813**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2001/0025959 A1	10/04/2001	Yamazaki et al.			02/21/2001
	AB	2001/0030322 A1	10/18/2001	Yamazaki et al.			02/02/2001
	AC	2002/0158288 A1	10/31/2002	Yamazaki et al.			02/21/2002
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

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Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.